

Measuring the Nanoworld

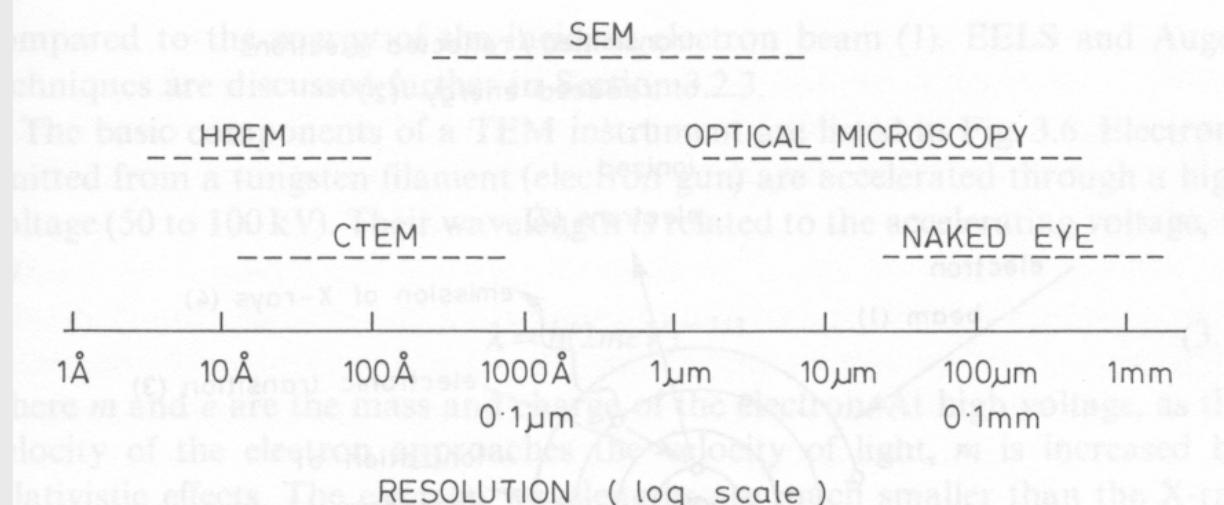
1. Electron Microscopy
2. Scanning Microscopies
3. Spectroscopies
4. Magnetic Measurements
5. Electric Measurements

30.10.2007

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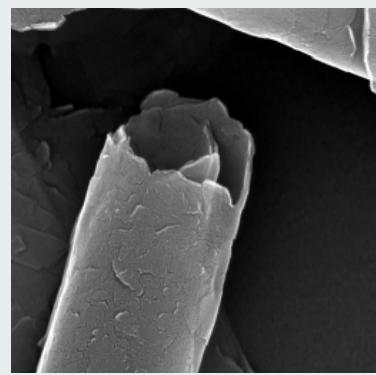
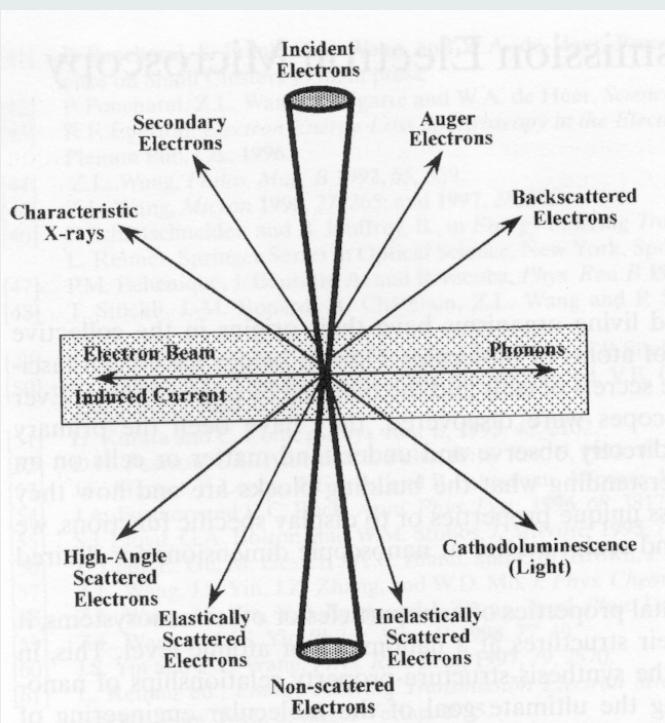
Microscopy



Scanning
surface methods

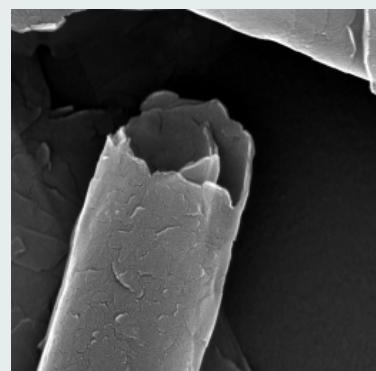
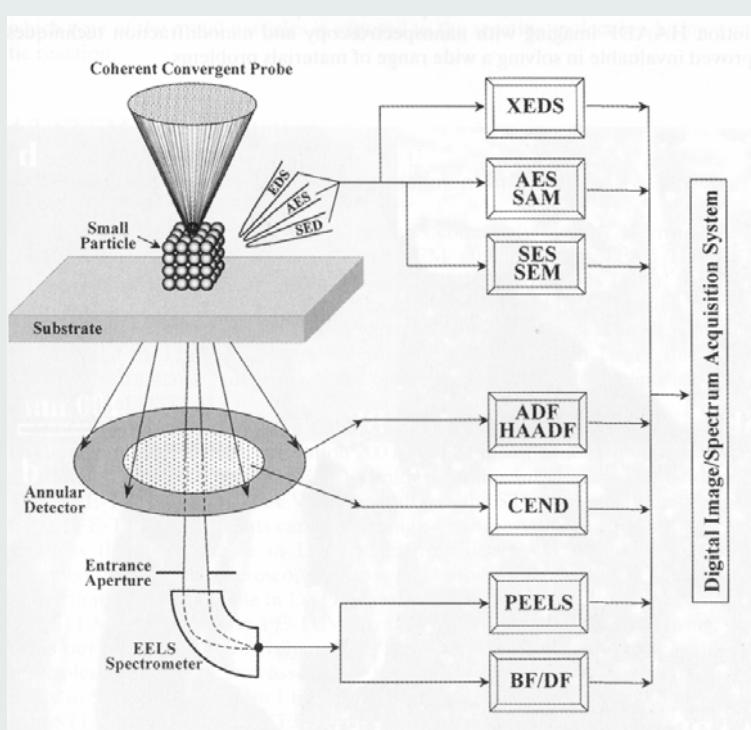
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Scanning Electron Microscopy



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Scanning Electron Microscopy - SEM



surface
analysis : 1 μ m

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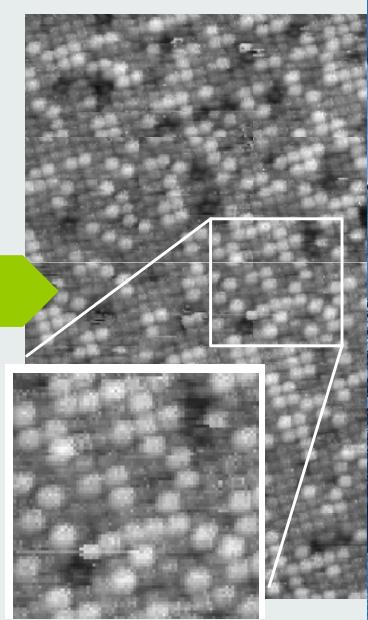
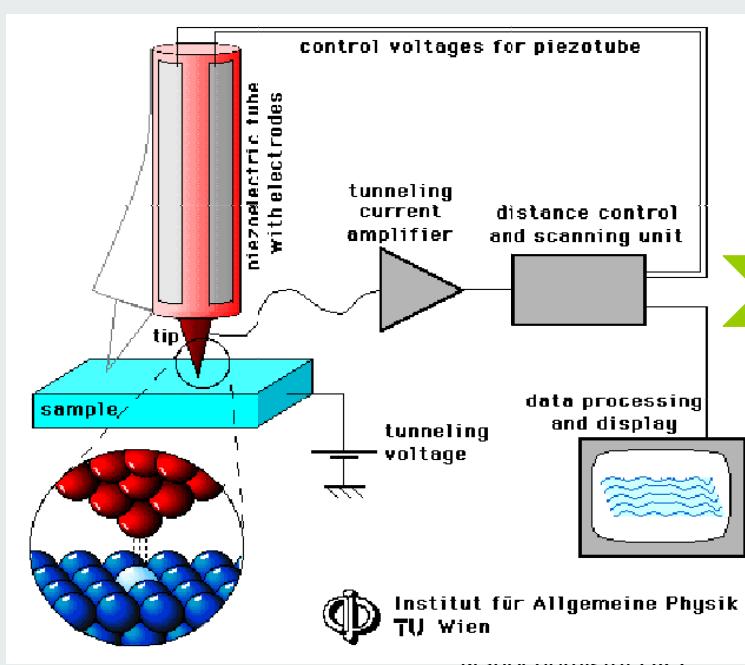
Scanning Probe Microscopies

1. Scanning tunneling Microscopy - STM
2. Atomic Force Microscopy - AFM
3. Magnetic Force Microscopy - MFM
4. Chemical Force Microscopies - CFM

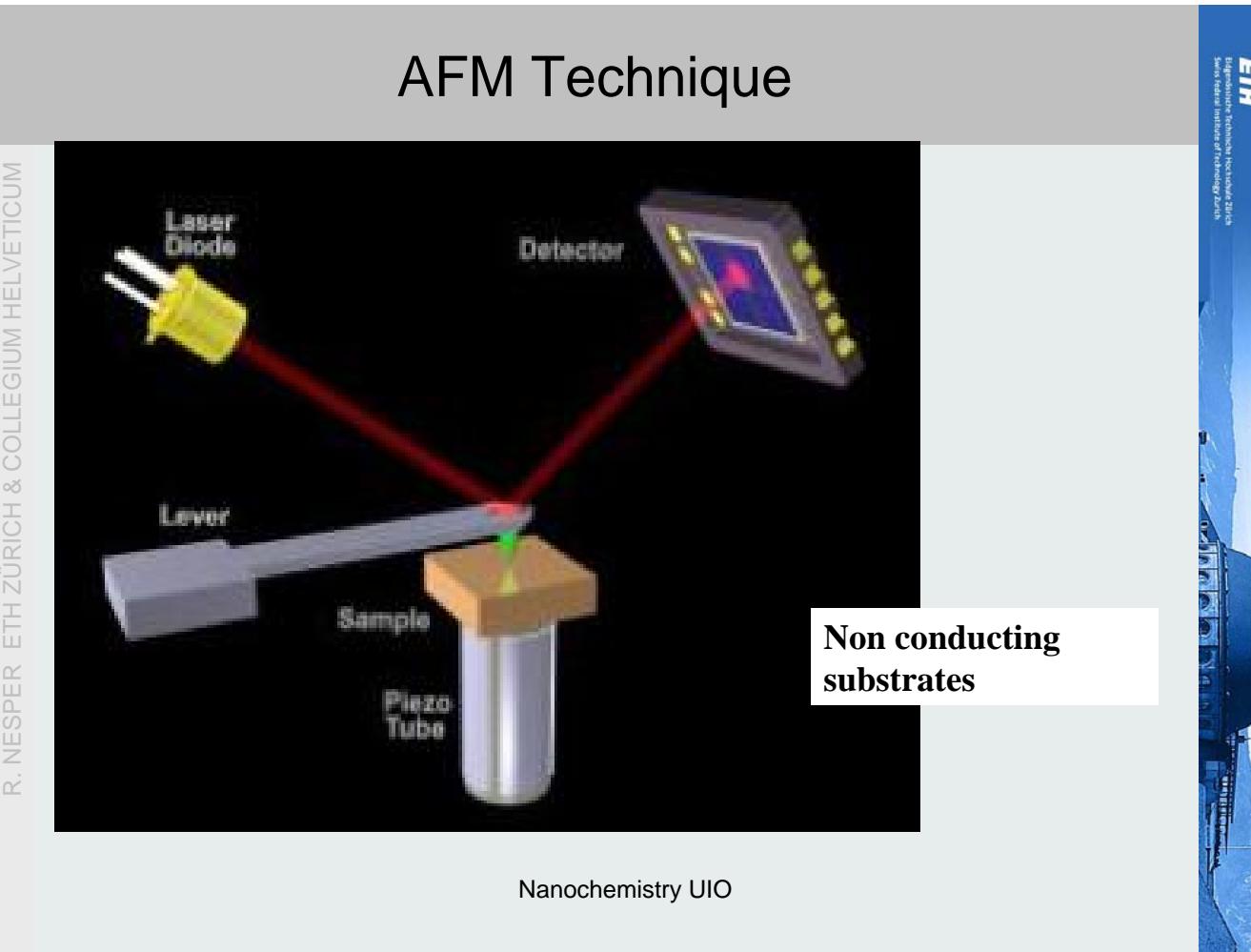
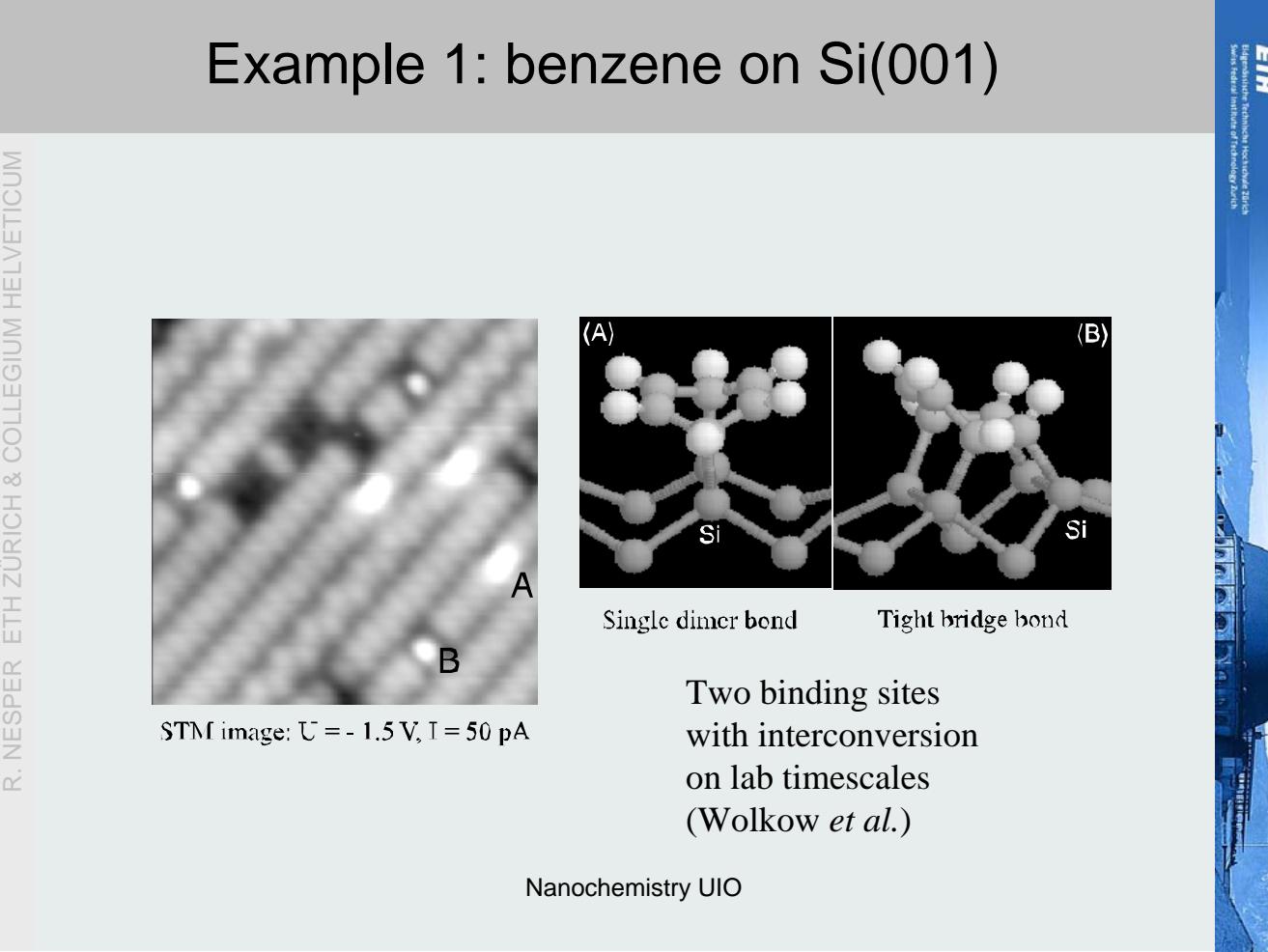
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Operation of an STM^{1,2}

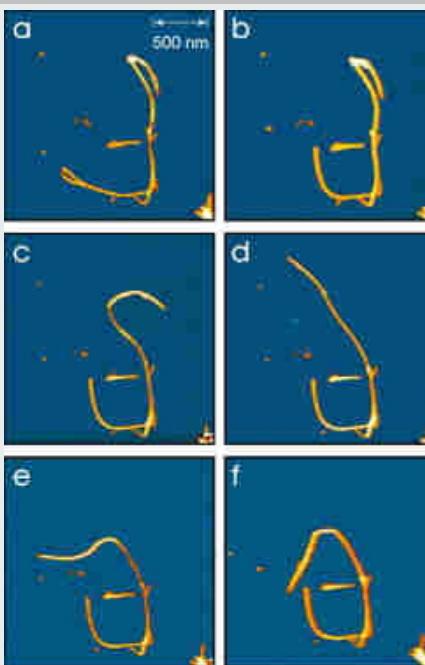
- [1] C. Julian Chen, *Introduction to Scanning Tunnelling Microscopy*, Oxford (1993)
[2] G.A.D. Briggs and A. J. Fisher, *Surf. Sci. Rep.* **33**, 1 (1999)



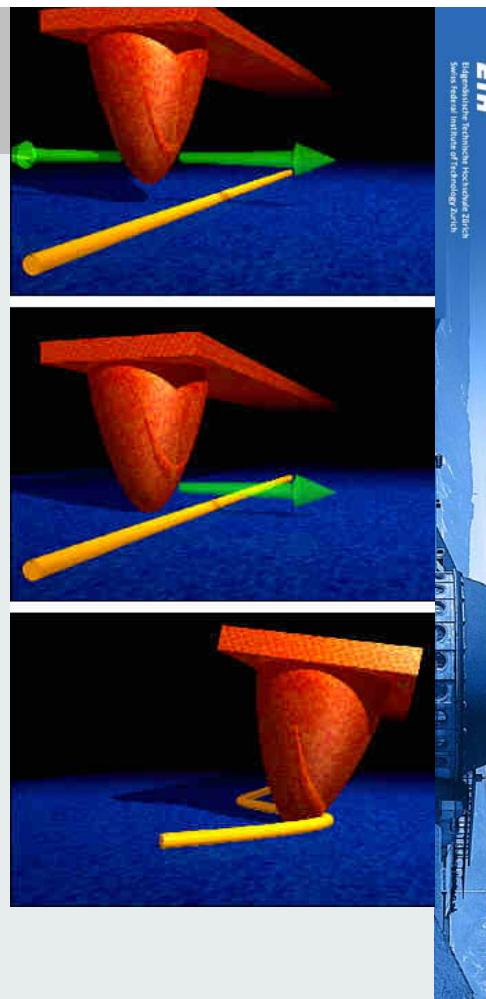
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Manipulation of Nano Objects

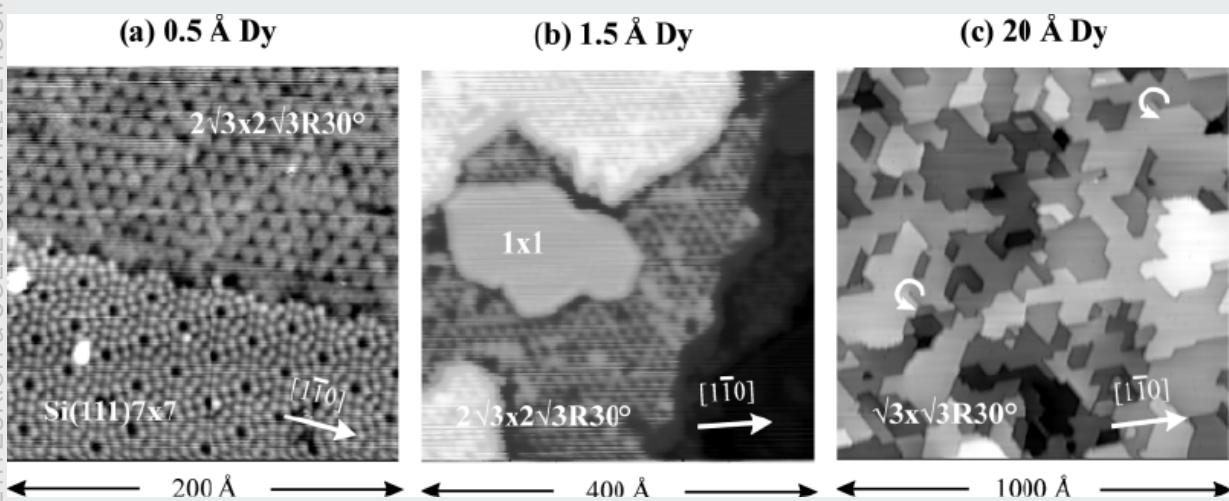


On the left another example of how a nanotube can be manipulated to form complex shapes: the 6 frames are a series of AFM images of a nanotube (orange) on a silicon substrate (blue). Not all steps are shown. The AFM tip is used to create the Greek letter "theta" from a 2.5 micron long nanotube.



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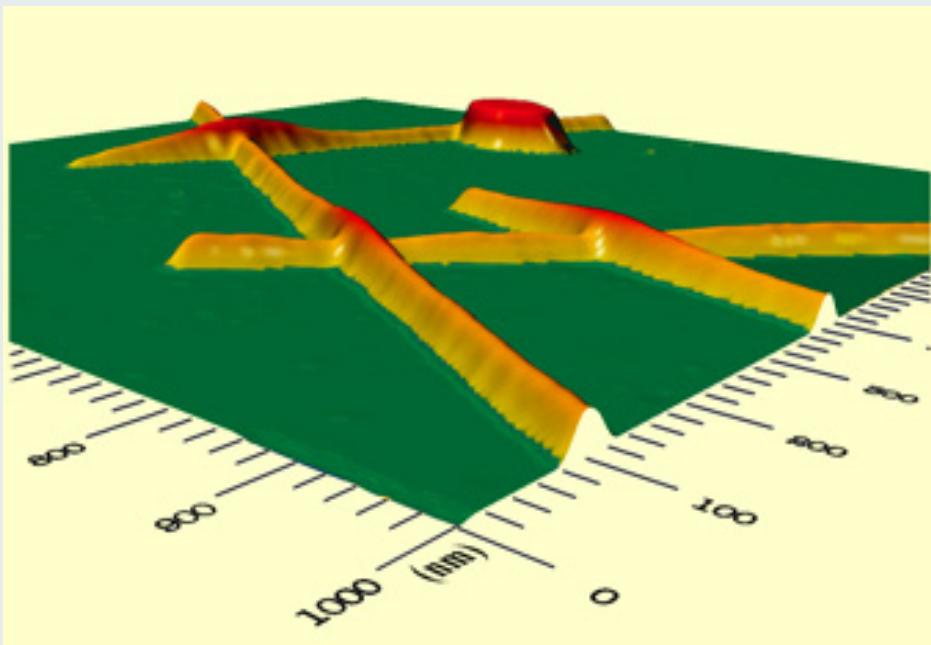
Example 1: benzene on Si(001)



The silicide films were grown by deposition of thin Gd, Dy, Er, and Lu films on clean Si(111)7x7 surfaces and subsequent annealing at temperatures of 500 - 600 ° C. In this way, the silicides are formed by solid-state diffusion of Ln and Si atoms. For the STM experiments, ultra-sharp tips prepared by ion bombardment were used.

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Scanning Probe Microscopies



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Physical Effects and Methods

	Phase identification	Amorphous or crystalline	Unit cell, space group	Crystal structure	Local structure, CN, etc.	Crystal defects	Surface structure	Polycrystalline texture	Elemental analysis	Electronic structure	Bond type
X-ray diffraction	(√)	(√)	(√)(√)	(√)	√	√	√	√	√	√	
Electron diffraction and microscopy		√	√	√	√	√	√	√	√	√	
Neutron diffraction				√	√	√	√	√	(√)	(√)	
Optical microscopy				√	(√)(√)				√	√	
IR spectroscopy	(√)	(√)	√	√							√
UV, visual spectroscopy	√	√	(√)	(√)	√						
NMR, ESR spectroscopy	(√)	(√)	(√)	(√)	√						(√)
Electron spectroscopy—ESCA, XPS, UPS, AES, EELS	√	√	√	√	√	(√)	√				
X-ray spectroscopy—XRF AEFS, EXAFS	(√)	(√)	√	√	(√)	√					
Mössbauer spectroscopy	(√)	(√)				√					

Physical Effects and Methods

EPMA	Electron Probe Micro Analysis	Analyse der charakteristischen Röntgenstrahlung oder der Elektronenstrahlung ⇒ Elementaranalyse
EMMA	Electron Microscopy with Micro Analysis	
AEM	Analytical Electron Microscopy	
XRF	X-ray Fluorescence (charakteristische) Röntgenstrahlung, Moseleysches Gesetz	Analyse leichter Elemente
EDX	Energy Dispersive X-ray-Analys	
EELS	Electron Energy Loss Spectroscopy	Analyse leichter Elemente
AES	Auger Electron Spectroscopy (Sekundärelektronen)	komplexe Spektren, bisher wenig untersucht
ESCA	Electron Spectroscopy for Chemical Analysis	$E_{\text{Einfall}}^{\nu} = E_{\text{Bind}}^{\text{Elektron}} + E_{\text{Kin.}}^{\text{Elektron}}$
XPS	X-ray Photoelectron Spectroscopy	$E_{\text{Kin.}}^{\text{Elektron}}$ wird gemessen ⇒ Elektronenstruktur von Feststoffen und Oberflächen
UPS	UV Photoelctron Spectroscopy	
AEFS	Absorption Edge Fine Structure (XANES)	Oxidationszustände,
EXAFS	Extended X-ray Absorption Fine Structure	lokale Umgebung ausgewählter Atome
ESR	Electron Spin Resonance	Elektronenkonfiguration
EPR	Electron Paramagnetic Resonance	lokale Umgebung
ENDDR	Electron Nuclear Double Resonance	lokale Fehlstellen
Mößbauer	γ -Strahlen-Resonanz	Elektronenstruktur
STM	Scanning Tunnel Microscopy	magnetische Struktur
LEED	Low Energy Electron Diffraction	Oberflächenstrukturen